

Supporting Information

The surface energy modulation of van der Waals interface in atomically thin semiconductor

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Figure S1. The morphology of a) MoSe₂, b) WS₂, and c) WSe₂ on S10 (top) and SiO₂ (bottom) surfaces.

Figure S2. The XPS spectra of the 1s orbital of Carbon, Fluorine, and Oxygen for a) SiO₂ and b) S10, respectively.

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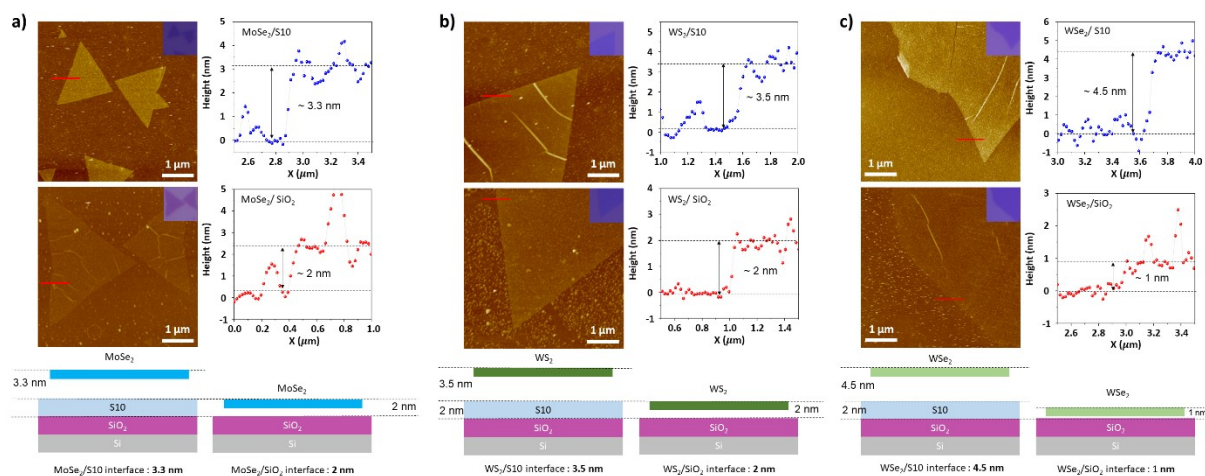


Figure S1. The morphology of a) MoSe₂, b) WS₂, and c) WSe₂ on S10 (top) and SiO₂ (bottom) surfaces.

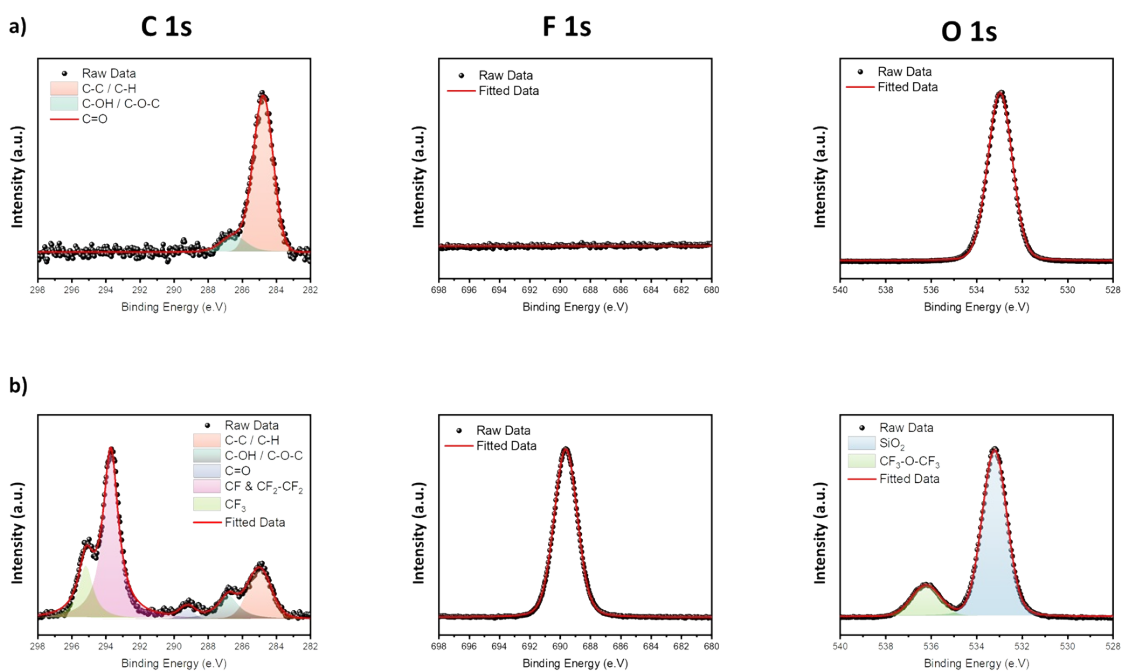


Figure S2. The XPS spectra of the 1s orbital of Carbon, Fluorine, and Oxygen for a) SiO₂ and b) S10, respectively.

Table S1. Electronegativity, bonding character, and dipole moment of TMDCs.

Atom	Electronegativity (χ)	TMDCs	Ionic bonding (%)	Covalent bonding (%)	Bond length (Å)	Dipole moment (Debye)
Mo	2.16	MoS ₂	4.31	95.69	2.42	0.50
W	2.36	MoSe ₂	3.73	96.27	2.49	0.45
S	2.58	WS ₂	1.20	98.80	2.40	0.14
Se	2.55	WSe ₂	0.90	99.10	2.49	0.11

Table S2. Binding energy of transition metal and chalcogenide in TMDCs on the SiO₂ and S10.

MoS₂					
Substrate	Binding Energy (eV)				
	Mo 3d _{5/2}	Mo 3d _{3/2}	S 2p _{3/2}	S 2p _{1/2}	
SiO₂	229.58	232.73	162.38	163.56	
S10	230.03	233.17	162.84	164.01	
Shift	0.45	0.44	0.46	0.45	

WS₂					
Substrate	Binding Energy (eV)				
	W 4f _{7/2}	W 4f _{5/2}	W 5p _{3/2}	S 2p _{3/2}	S 2p _{1/2}
SiO₂	33.43	35.59	38.95	163.11	164.31
S10	32.74	34.74	37.48	162.22	163.41
Shift	-0.69	-0.85	-1.47	-0.89	-0.9

MoSe₂					
Substrate	Binding Energy (eV)				
	Mo 3d _{5/2}	Mo 3d _{3/2}	Se 3d _{5/2}	Se 3d _{3/2}	
SiO₂	229.03	232.18	54.43	55.3	
S10	229.11	232.23	54.53	55.37	
Shift	0.08	0.05	0.1	0.07	

WSe₂					
Substrate	Binding Energy (eV)				
	W 4f _{7/2}	W 4f _{5/2}	W 5p _{3/2}	Se 3d _{5/2}	Se 3d _{3/2}
SiO₂	32.58	34.75	38.05	54.85	55.68
S10	32.02	34.19	37.66	54.28	55.12
Shift	-0.56	-0.56	-0.39	-0.57	-0.56

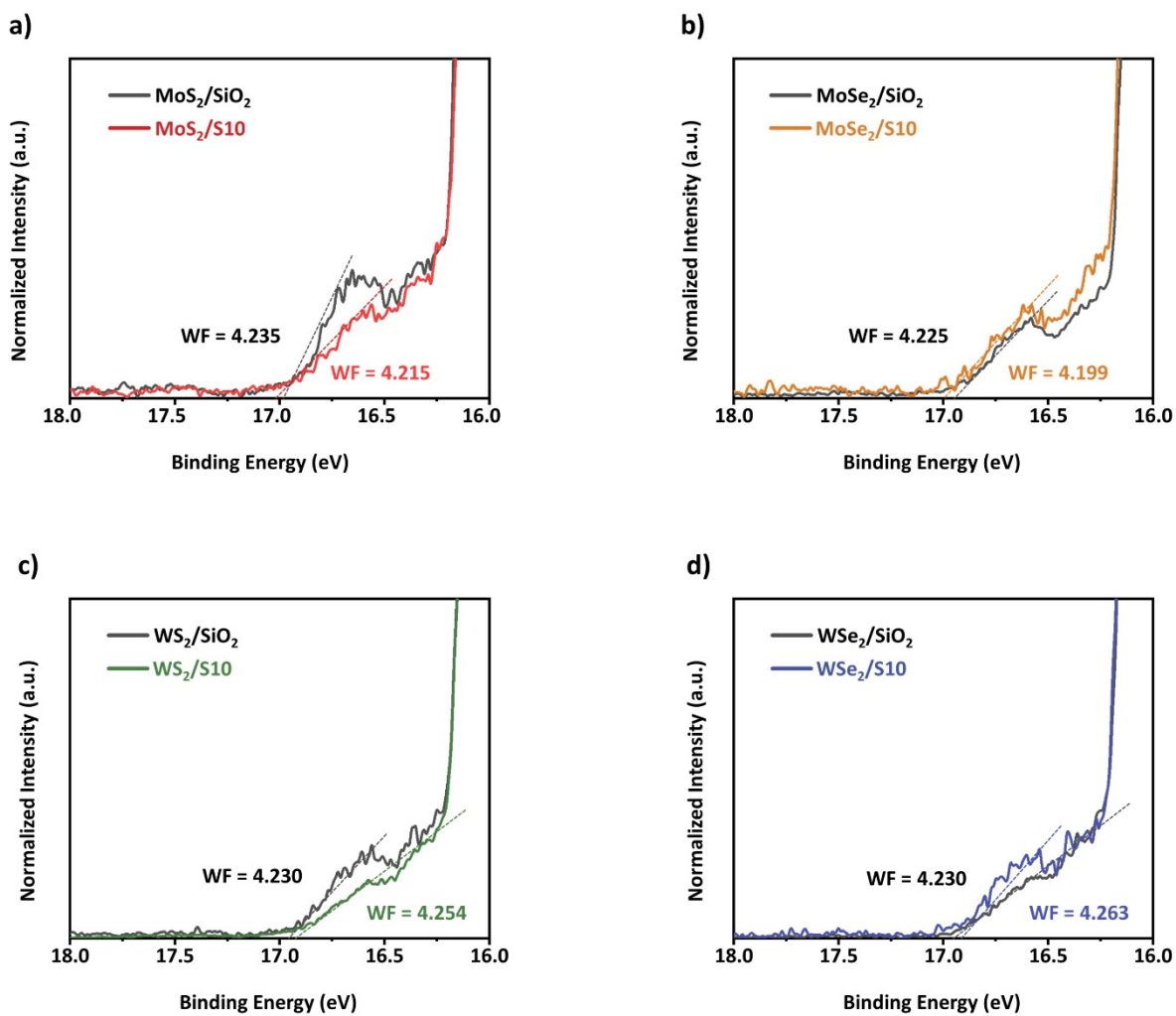


Figure S3. Ultraviolet photoelectron spectroscopy of TMDCs on SiO₂ and S10, respectively.

a) MoS₂, b) MoSe₂, c) WS₂, and d) WSe₂.

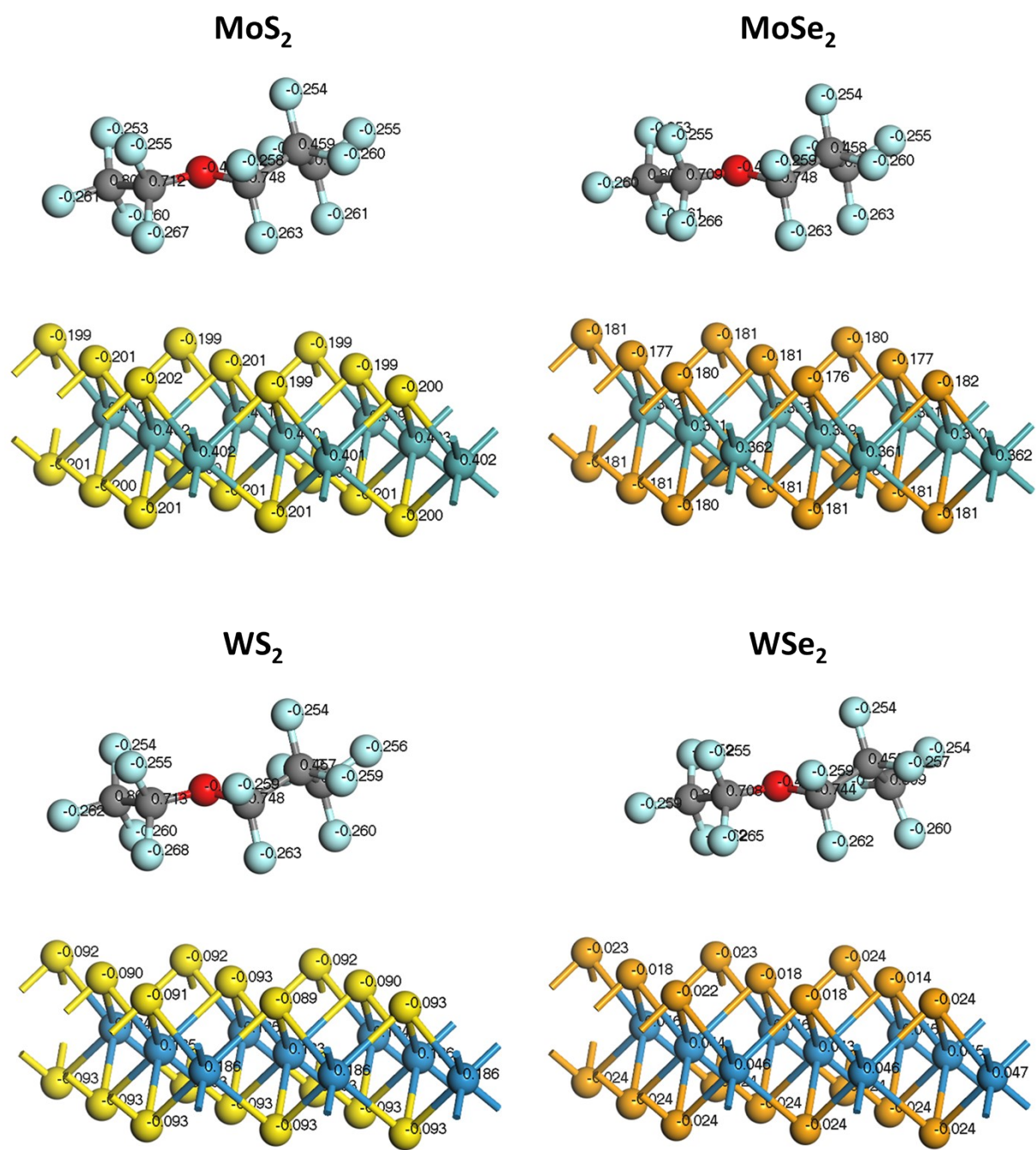


Figure S4. The atomic charge distribution of TMDCs/S10 heterostructure through Mulliken analysis.

Table S3. The changes of dipole moment depending on S10.

TMDCs	Bond length (Å)	Intrinsic Dipole moment (Debye)	Induced Dipole moment with S10 (Debye)
MoS₂	2.42	0.50	0.93
MoSe₂	2.49	0.45	0.78
WS₂	2.40	0.14	0.19
WSe₂	2.49	0.11	0.01

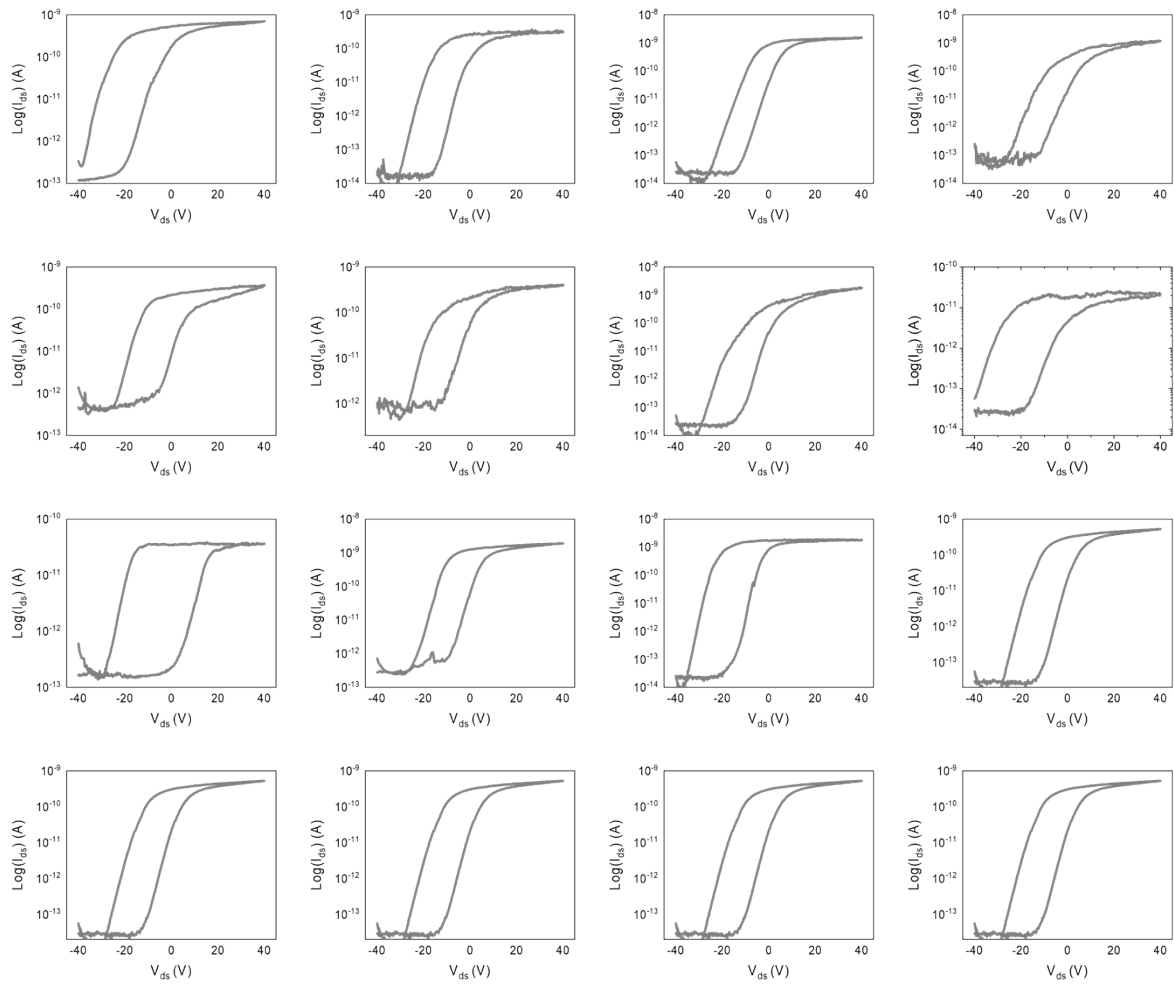


Figure S5. The electrical transport of pristine MoS₂ devices.

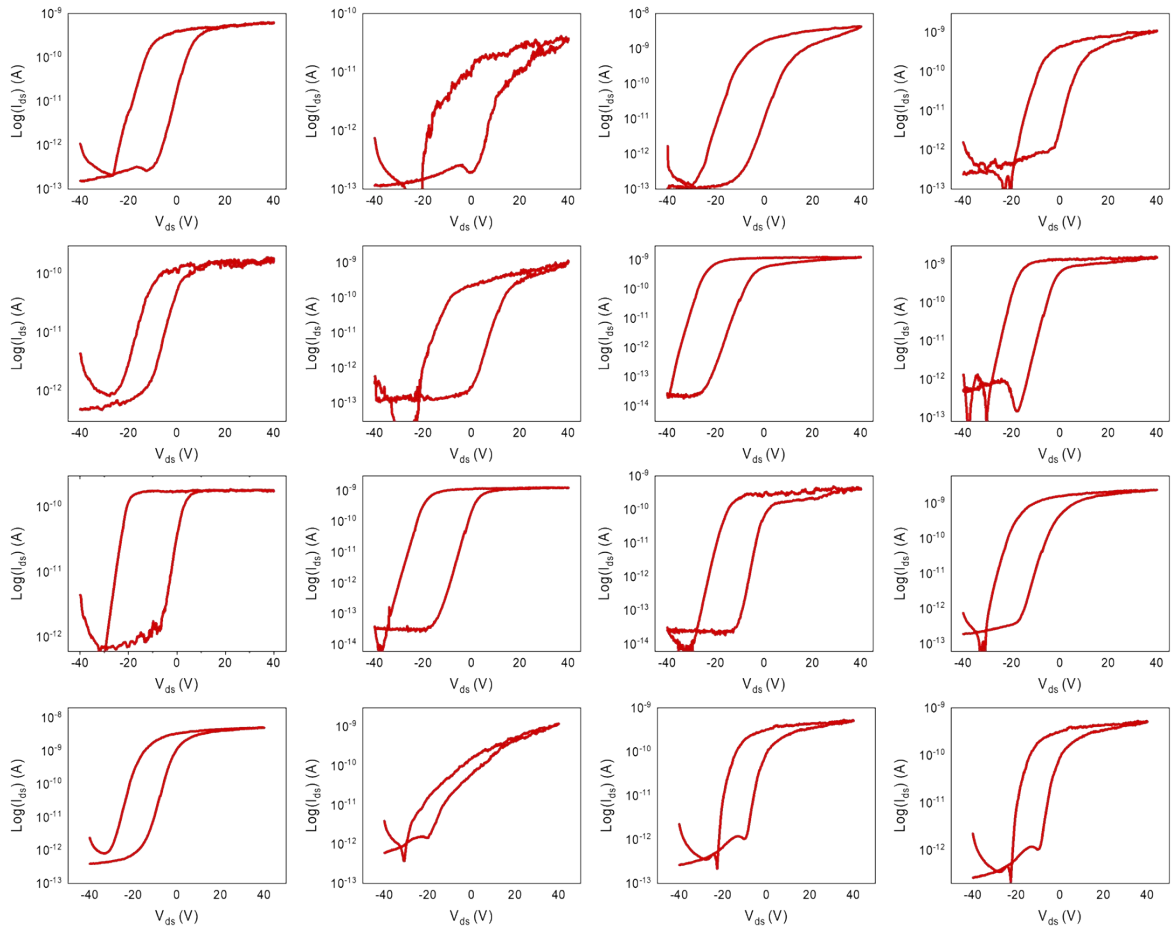


Figure S6. The electrical transport of pristine MoS₂/S10 devices.

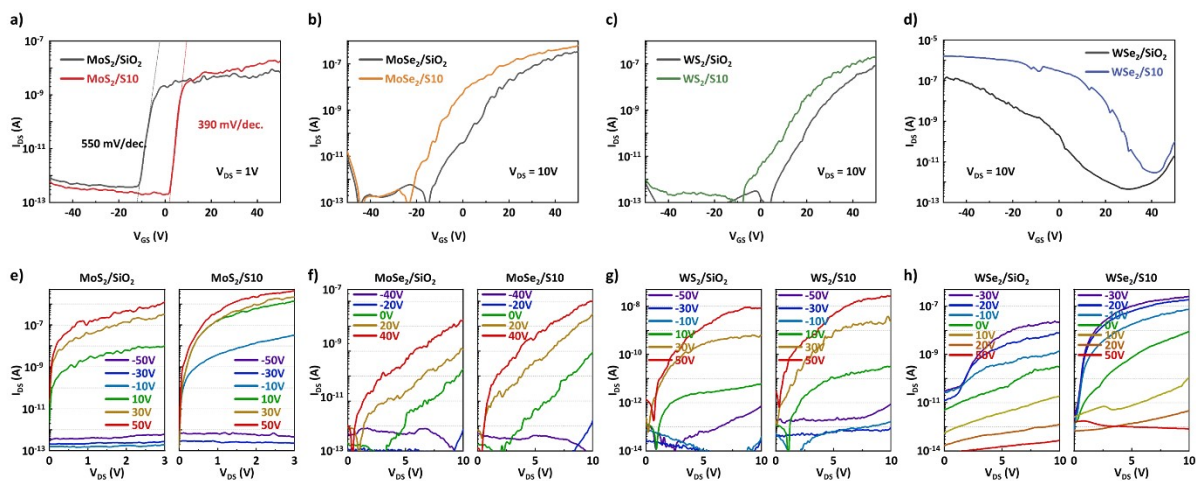


Figure S7. The comparison of electrical properties for the devices of TMDCs monolayer on S10 and SiO₂, respectively. The transfer curves of a) MoS₂, b) MoSe₂, c) WS₂, d) WSe₂ and the output curves of e) MoS₂, f) MoSe₂, g) WS₂, h) WSe₂ are presented, respectively.

Table S4. The comparison of field effect mobility and subthreshold swing in TMDCs monolayer on SiO₂ and S10.

TMDCs	MoS ₂		MoSe ₂		WS ₂		WSe ₂	
	SiO ₂	S10	SiO ₂	S10	SiO ₂	S10	SiO ₂	S10
Field effect mobility (cm²/Vs)	0.042	0.082	0.123	0.251	0.089	0.185	0.140	0.301
SS (mV/dec.)	550	390	2,790	1,720	6,100	3,190	3,690	1,560

Supporting Note 1

To determine the electron populations of transition metal dichalcogenides (TMDCs) when perfluoropolyether (PFPE) approaches, we performed quantum mechanical calculations using DMOL3 code as implemented in the BIOVIA Materials Studio platform. The double numeric atomic orbitals with polarization for the basis sets, and all electrons, with a relativistic effect considered for the core parts, were used during calculation. The exchange-correlation functionals with generalized gradient approximation¹, and the k -points samplings by Monkhorst-Pack grid with equidistance of 0.02 \AA^{-1} were chosen. The lattice constants of optimized bulk TMDCs using calculational parameters listed above follows: $a = b = 3.19 \text{ \AA}$ and $c = 14.88 \text{ \AA}$ for MoS_2 , $a = b = 3.33 \text{ \AA}$ and $c = 15.45 \text{ \AA}$ for MoSe_2 , $a = b = 3.19 \text{ \AA}$ and $c = 14.20 \text{ \AA}$ for WS_2 , and $a = b = 3.30 \text{ \AA}$ and $c = 15.07 \text{ \AA}$ for WSe_2 . The optimized structures are well matched with previous results: $a = b = 3.15 \text{ \AA}$ and $c = 12.3 \text{ \AA}$ for MoS_2 , $a = b = 3.3 \text{ \AA}$ and $c = 13.0 \text{ \AA}$ for MoSe_2 , $a = b = 3.15 \text{ \AA}$ and $c = 12.32 \text{ \AA}$ for WS_2 , and $a = b = 3.29 \text{ \AA}$, and $c = 12.98 \text{ \AA}$ for WSe_2 .

From the optimized geometry, we generated (3×3) supercell and cleaved the $(0\ 0\ 1)$ surface to consider the population differences of surface. After that, we applied 60 \AA of vacuum slab to exclude interlayer interaction. The monomer of PFPE was used to accelerate the simulation. To consider the actual experimental conditions, we first modeled PFPE on the TMDCs surface with a 1 \AA distance. As a result of geometry optimization, the distance between PFPE and TMDCs surface became 3 \AA naturally due to Coulomb interaction matching to AFM measurement. After that, the contributions to the atomic charge from each atomic orbital on each atom were calculated using Mulliken-analysis method.

Supporting Note 2

The calculation for the changes of dipole moment on S10 was conducted using the equation shown below:

$$\mu = q \cdot r$$

μ , q , r are dipole moment, separated charge, and bond length of transition metal and chalcogen, respectively. The separated charge of TMDs by S10 was calculated by the equation, $q = ed_c$, (e : a charge of electron, d_c : atomic charge distribution in figure S3).

Supporting Note 3

The field-effect mobility (μ_{FE}) for each TMDC were calculated using the following equations:

$$\mu_{FE} = \frac{g_m L}{WC_{ox} V_{DS}}$$

where, g_m is the maximum back-gated transconductance. L and W are the length (8 μm) and width (25 μm) of the channel, respectively. C_{OX} ($=\epsilon_0 \cdot \epsilon_r / d$; $\epsilon_r=3.9$) represents the back-gate capacitance of SiO₂ (300 nm). V_{DS} is the drain-source voltage.

The subthreshold swing (SS) of devices were calculated using the equation shown below:

$$SS = \left(\frac{d(\log_{10} I_{DS})}{dV_{GS}} \right)^{-1}$$

References

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